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ELECTRICAL MEASUREMENT  
AND ANALOGUE ELECTRONICS

June/July 2016

Time: 3 hours



THE KENYA NATIONAL EXAMINATIONS COUNCIL

DIPLOMA IN ELECTRICAL AND ELECTRONIC ENGINEERING  
(INSTRUMENTATION OPTION)  
(TELECOMMUNICATION OPTION)  
(POWER OPTION)

## MODULE I

ELECTRICAL MEASUREMENT AND ANALOGUE ELECTRONICS

3 hours

## INSTRUCTIONS TO CANDIDATES

*You should have the following for this examination:**Drawing instruments;**Non-programmable electronic calculator;**Mathematical tables.**This paper consists EIGHT questions into TWO sections; A and B.**Answer any THREE questions from section A and any TWO questions from section B in the answer booklet provided.**All questions carry equal marks.**Maximum marks for each part of a question are as shown.**Candidates should answer the questions in English.*

This paper consists of 5 printed pages.

Candidates should check the question paper to ascertain that all the pages are printed as indicated and that no questions are missing.

## SECTION A: ELECTRICAL MEASUREMENTS

Answer any **THREE** questions in this section.

1. (a) Define the following system of units as applied in measurements:  
(i) absolute unit;  
(ii) derived unit. (2 marks)
- (b) Derive the dimensions of the following quantities using the electrostatic system of units:  
(i) charge (Q);  
(ii) current (I). (8 marks)
- (c) State **four** advantages of the MKS system of units in electrical measurements. (4 marks)
- (d) Using the LMTI system of units, derive the dimensional equations for:  
(i) EMF;  $= \frac{\text{work}}{\text{charge}}$   
(ii) magnetic flux density.  $= \frac{\text{force}}{\text{current} \times \text{length}}$  (6 marks)
2. (a) Explain the following types of measurement errors:  
(i) environmental errors; - due to external conditions  
(ii) instrumental errors; - due to the fault of the instrument  
(iii) gross errors; - error due to human mistake  
(iv) residue errors; - errors due to the level of cleaning  
Random - accidental - small one (8 marks)
- (b) State **three** detectors and their operational frequencies as commonly used for a.c. bridges.  
Diodes  
Resonance  
Induction (6 marks)
- (c) Explain how the following factors affect precision measurement of medium resistance with wheatstone bridge:  
(i) temperature effects;  
(ii) contact resistance;  
(iii) thermo-electric effects. (6 marks)
3. (a) State **three** causes of faults on a printed circuit board. (3 marks)
- (b) List **five** tools used in the repair and maintenance of electronic equipment. (5 marks)
- (c) Explain **three** points a service engineer should consider when fault finding on electronic equipment. (6 marks)
- (d) Outline **three** operational objectives and **three** cost objectives of good maintenance. (6 marks)

(a) Describe the term 'reliability' as applied in electrical measurements. (4 marks)

It is the ability of a measuring to perform operational tasks without failure over a given time under specified conditions.

(b) Explain the importance of the following in relation to reliability:

- (i) mean time between failures; - Time when the machine will stop the work.
- (ii) mean time to failure; - To serve the purpose when in good condition.
- (iii) availability. - the availability of a measuring machine to serve the specified purpose. (6 marks)

(c) Table 1 shows the performance of ten pressure monitors, observed while operating for a period of 1200 hours. Every failed unit is replaced immediately. Determine the:

- (i) MTBF;
- (ii) failure rate

(10 marks)

Table 1

Unit Number	Time of Failure (hours)	Failure
1	650	1
2	420	1
3	130 and 725	2
4	585	1
5	630 and 950	2
6	390	1
7	No failure	0
8	880	1
9	No failure	0
10	220 and 675	2

(a) State three reasons for the inaccuracies encountered in magnetic measurements.

(3 marks)

(b) Outline six methods of fault location in electronic systems.

(6 marks)

(c) Explain the following wattmeter errors:

- (i) eddy current errors;
- (ii) stray magnetic field errors.

(6 marks)

(d) Draw a labelled construction diagram of Hibberts magnetic standard used in magnetic measurements.

(5 marks)



## SECTION B: ANALOGUE ELECTRONICS

Answer any **TWO** questions from this section.

1.2

12.5.46

6. (a) Explain how the following extrinsic semi-conductors are formed.

- (i) N-type; - formed by adding pentavalent atoms.  
 (ii) P-type; - formed by adding trivalent atoms. (4 marks)

- (b) (i) State **three** applications of semi-conductor diodes - as a switch, photo diode, LED, light emitting diode.  
 (ii) With aid of voltage-current characteristics, describe the avalanche breakdown in a P-N junction diode. (10 marks)

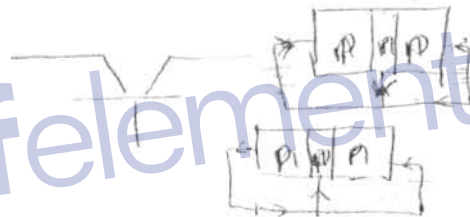


- (c) A silicon diode has a forward voltage drop of  $1.5V$  and a forward d.c. current of  $150mA$ . It has a reverse current of  $1.2 \mu A$  and a reverse voltage of  $12V$ .  
 Determine for the diode the:

- (i) forward resistance;  $R_F = \frac{V_F}{I_F} = \frac{1.5V}{150mA} = 10m\Omega$   
 (ii) reverse resistance;  $R_R = \frac{V_R}{I_R} = \frac{12V}{1.2\mu A} = 10M\Omega$  (6 marks)

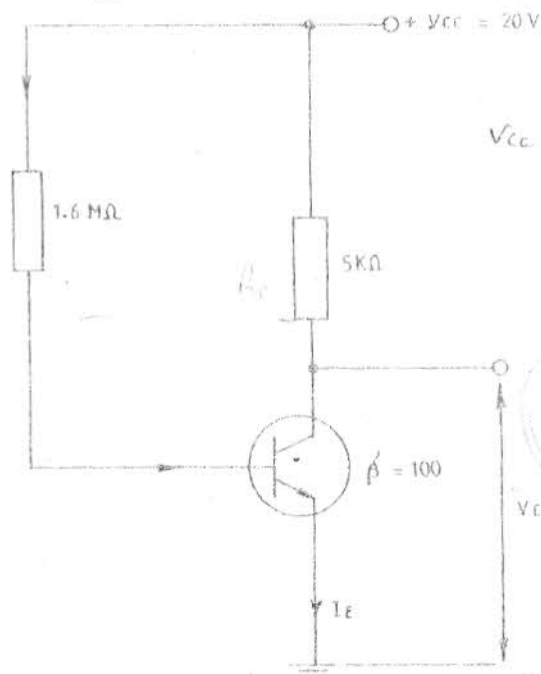
7. (a) Draw equivalent two source biasing circuits using the transistor symbol for the following:

- (i) PNP transistor;  
 (ii) NPN transistor. (4 marks)



- (b) Figure 1 shows an amplifier circuit.

- (i) Determine the d.c. operating point.  
 (ii) Sketch the d.c. loadline. (12 marks)

NB: neglect  $V_{BE}$ 

$$V_{CC} \quad I_{C(sat)} = \frac{V_{CC}}{R_B + R_C}$$

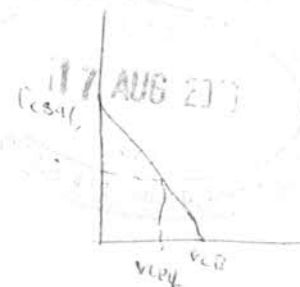


Fig. 1

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- (c) State **two** advantages and **two** disadvantages of field effect transistors over bipolar junction transistors. (4 marks)
8. (a) State **three** advantages of bridge rectifier over bi-phase rectifier. (3 marks)
- (b) (i) With aid of circuit diagram and voltage waveforms, describe the operation of a single phase half wave rectifier feeding a purely resistive load. (11 marks)
- (ii) Derive the expression for the output d.c. current for the rectifier in b(i).
- (c) Figure 2 shows a zener diode stabilizer. Determine the output voltage with no load current. (6 marks)

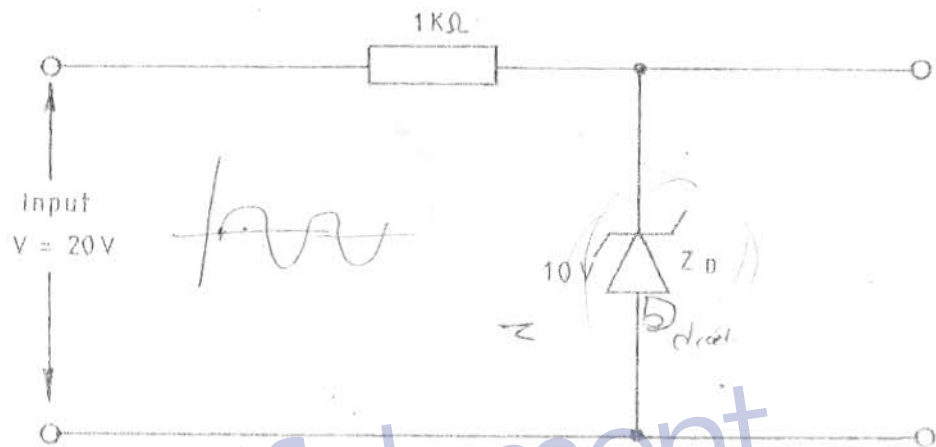


Fig. 2

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